



**WANSEMI**  
万芯半导体

**WP8810E**

# **Enhancement Mode N-Channel Power MOSFET**

**TSSOP8/NMOS/20V/ $\pm 10V$ /0.7V/5A/13.5m $\Omega$**

**Rev0.6**

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## 20V, 13.5mΩ, 5A, N-Channel Enhancement Mode Power MOSFET

### 1.Features

- ◆ High Power and current handling capability
- ◆ Lead free product is acquired
- ◆ Surface Mount Package
- ◆ ESD Rating: HBM 2KV

V <sub>DS</sub> Typ	R <sub>DS(on)</sub> Typ.	I <sub>D</sub> Max.
20V	13.5mΩ @ 4.5V	5A
	18mΩ @ 2.5V	

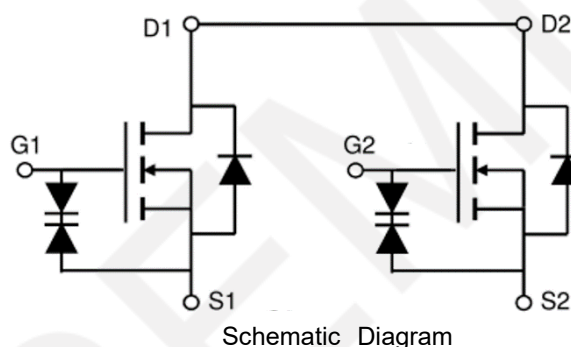
### 2.Applications

- ◆ Battery protection
- ◆ Load Switch
- ◆ Power management



TSSOP8

Pin Description



### 3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP8810E	8810E	TSSOP8	5,000	80,000

### 4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V <sub>DSS</sub>	20	V
Gate to Source Voltage	V <sub>GSS</sub>	±10	V
Drain Current-Continuous	I <sub>D</sub>	5	A
Pulsed Drain Current	I <sub>DM</sub>	20	A
Power Dissipation	P <sub>D</sub>	0.9	W

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### 5.Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction to Ambient (Note 2)	R <sub>θJA</sub>	139	°C/W

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

**6. Electrical Characteristics at Ta=25°C (Note 3)**

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu A, V_{GS} = 0V$	20	23		V
Zero- Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 20V, V_{GS} = 0V$			1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS} = \pm 10V, V_{DS} = 0V$			$\pm 10$	$\mu A$
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{DS} = 250\mu A$	0.4	0.7	1.0	V
Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 5A, V_{GS} = 4.5V$		13.5	17	m $\Omega$
		$I_D = 3A, V_{GS} = 2.5V$		18	23	m $\Omega$
Diode Forward Voltage	$V_{SD}$	$I_S = 5A, V_{GS} = 0$		0.84	1.2	V
Input Capacitance	$C_{iss}$	$V_{GS} = 0V,$ $V_{DS} = 10V,$ Frequency=1.0MHz		545		pF
Output Capacitance	$C_{oss}$			103		pF
Reverse Transfer Capacitance	$C_{rss}$			90		pF
Turn-ON Delay Time	$t_{d(on)}$	$V_{DS} = 10V,$ $V_{GS} = 5V,$ $R_{GEN} = 3\Omega,$ $R_L = 1.5\Omega$		0.5		ns
Turn-ON Rise Time	$t_r$			1		ns
Turn-OFF Delay Time	$t_{d(off)}$			12		ns
Turn-ON Fall Time	$t_f$			4		ns
Total Gate Charge	$Q_g$	$V_{DS} = 10V,$ $V_{GS} = 4.5V,$ $I_D = 5A$		8		nC
Gate- Source Charge	$Q_{gs}$			2.5		nC
Gate- Drain Charge	$Q_{gd}$			3		nC

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

## 7. Typical electrical and thermal characteristics

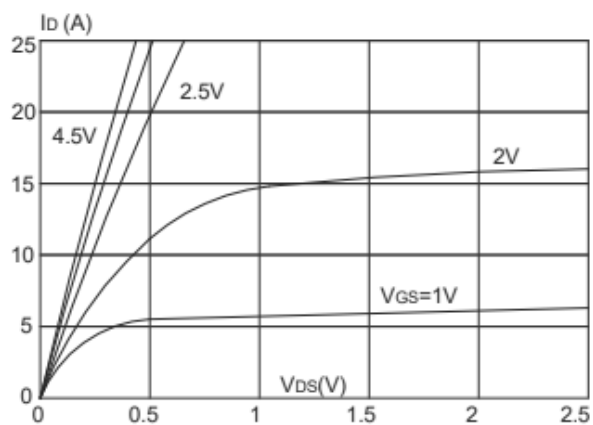


Figure 1 On-Region Characteristics

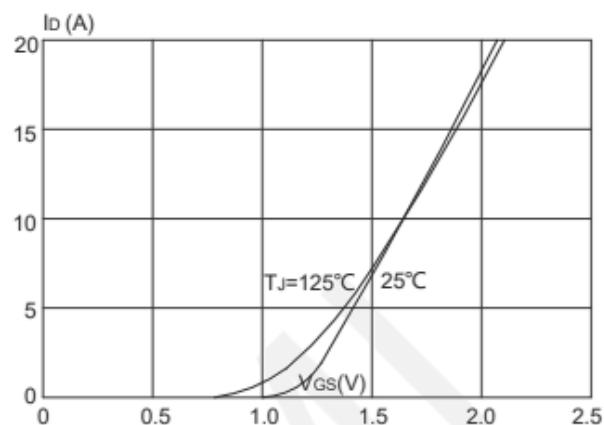


Figure 2 Transfer Characteristics

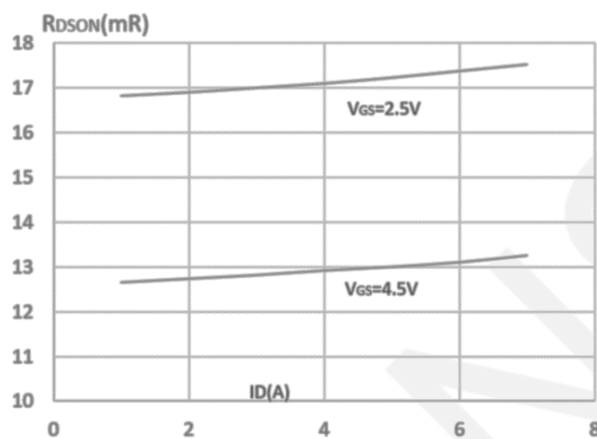


Figure 3 On-Resistance vs. Drain Current and Gate Voltage

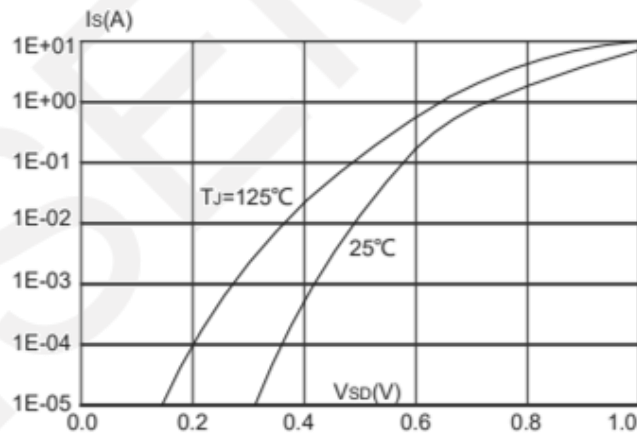


Figure 4 Body Diode Characteristics

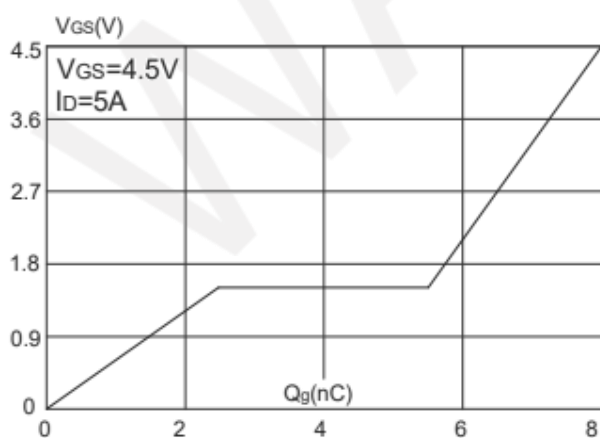


Figure 5 Gate Charge Characteristics

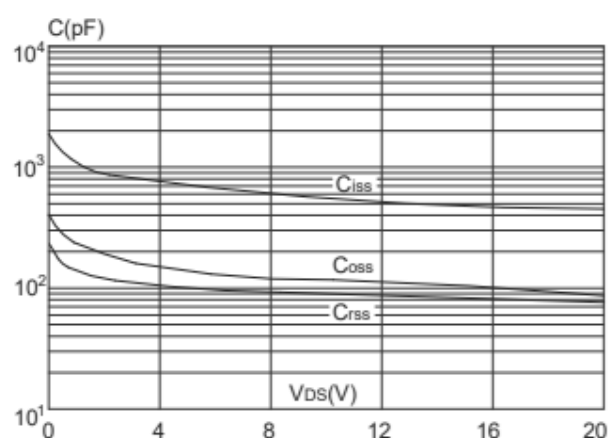


Figure 6 Capacitance Characteristics

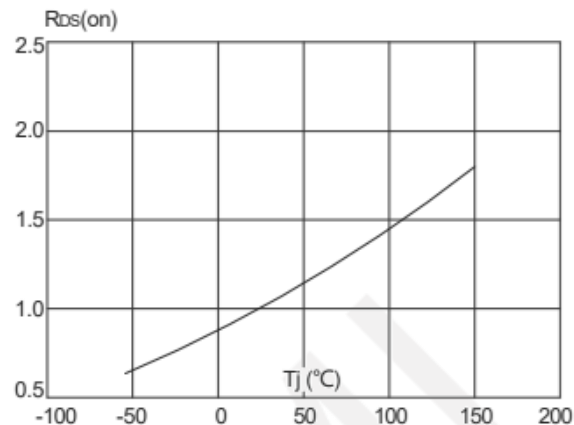
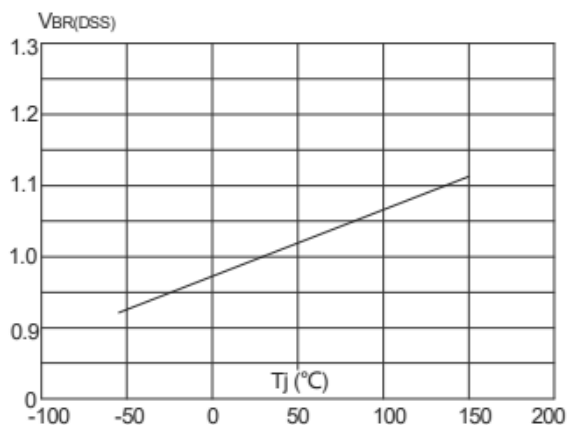


Figure 8 Normalized on Resistance vs. Junction Temperature

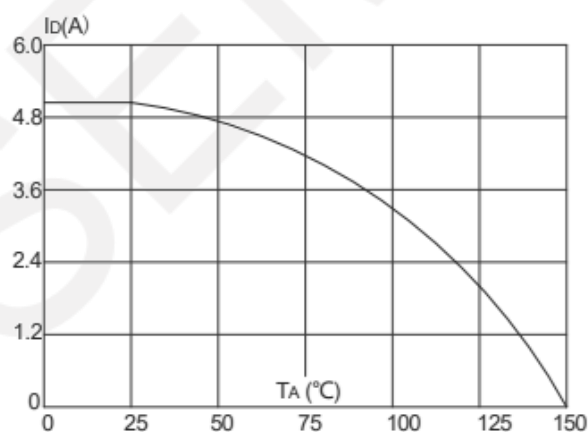
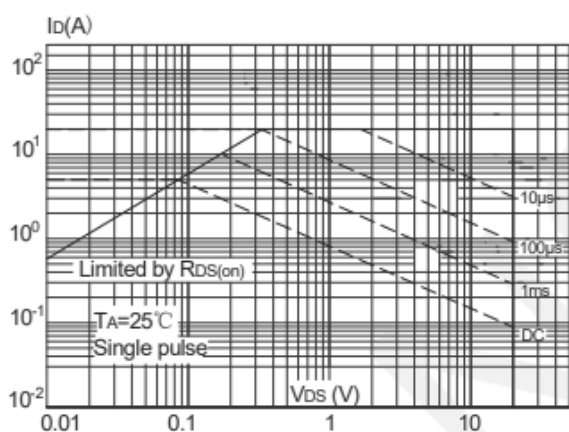


Figure 9 Maximum Forward Biased Safe Operating Area

Figure 10 Single Pulse Power Rating Junction-To-Ambient

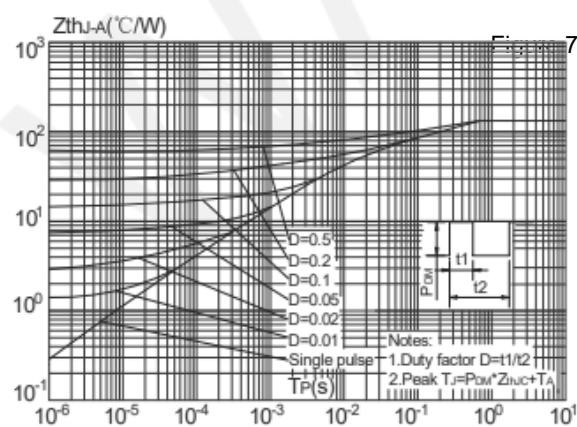
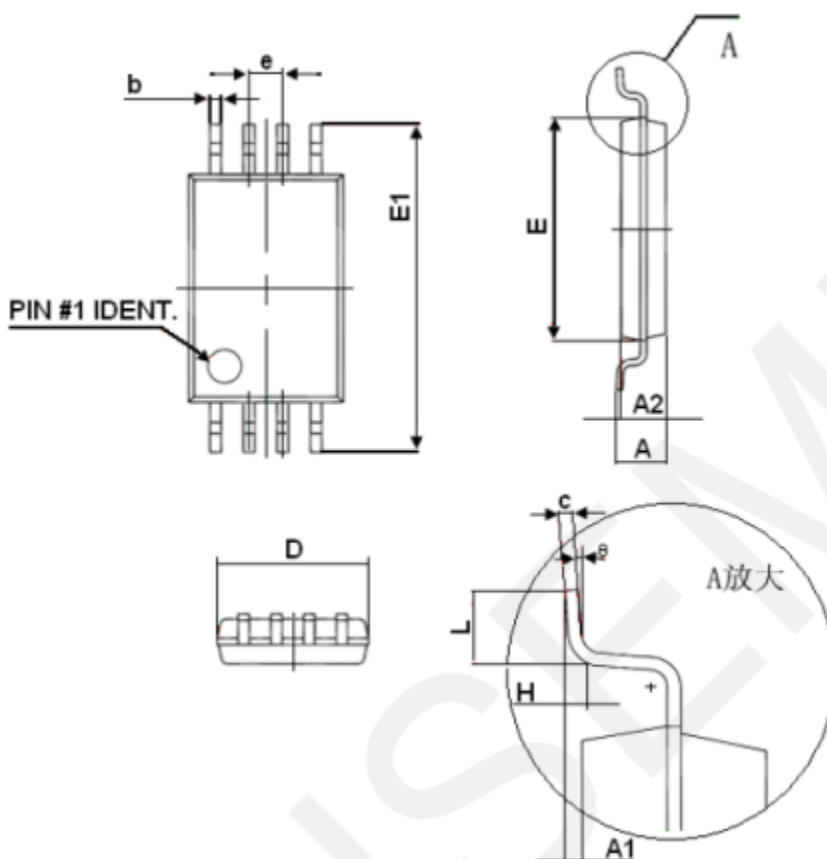


Figure 7 Normalized Breakdown Voltage vs. Junction Temperature

Figure11 Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

## 8.Package Dimensions



Symbol	Dimensions In Millimeters	
	Min	Max
D	2.900	3.100
E	4.300	4.500
b	0.190	0.300
c	0.090	0.200
E1	6.250	6.550
A		1.100
A2	0.800	1.000
A1	0.020	0.150
e	0.65(BSC)	
L	0.500	0.700
H	0.25(TYP)	
⊙	1°	7°

## **9.Important Notice**

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